PCN Number:		20100813000XB					PCN Date: 03/28/2013				
Title: Assembly Site move to CAR for Select Devices in the SSOP (DB) Package											
Custom	ner Contact:	PCN	I Ma	anager Phoi	1e: +1(214	1)480-60	337	Dept: Quality Services			
Proposed 1 st Ship Da		te:		09/28/2013	Estimate Availabili		nple Date provided at sample request				
Change Type:							· · ·				
	embly Site		Assembly Process Assembly N				Assembly Materials				
Des			Ħ	Electrical Specification			$\overline{\Box}$	Mechanical Specification			
	t Site		$\overline{\boxtimes}$				$\overline{\Box}$	Test Process			
Wat	fer Bump Site			Wafer Bump Material				Wafer Bump Process			
	fer Fab Site			Wafer Fab Materials				Wafer Fab Process			
PCN Details											
Description of Change:											
Final notifications of Assembly Site move to CAR for Select Devices in the SSOP (DB) Package which are currently assembled at CRS. This also includes a change on the MSL level as follows: From To Moisture Sensitivity MSL 1, 260C MSL 2, 260C											
Reason for Change:											
Continuity of supply.											
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):											
None.											
Change	s to product i	den	tif	ication result	ing from tl	his PCN	l:				
Sample Product Shipping Label (not actual product label) Assembly Site CRS Assembly Site Origin (22L) ASO: CRS											
CAR		Assembly Site Origin (22L)				ASO: CAR					
TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L) TO: 1750 (1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ACO: MYS											
Product Affected:											
PCM42	02IDBREP	Vé	52/	07642-01XE							

DB Qualification Data: Approved 3/21/2013

This qualification has been specifically developed for the validation of this change. The

qualification data validate specifications.	s that the	e proposed ch	ange meets the applica	ble released technical			
	Qual Dev	vice 1 : ADS	31213E (MSL 2-260C)				
Package Construction Details							
Assembly Site:	CAR		Mold Compound:	438360			
# Pins-Designator, Family:	28-DB, S	SOP	Mount Compound:	434165			
Leadframe (Finish, Base):	NiPdAu, (Cu	Bond Wire:	1.3 Mil Dia., AU			
Qualification: Plan	n 🛚 Te	est Results					
Reliability Test		Conditions		Sample Size Pass/Fail			
**Unbiased HAST		130C/85%R	H/33.3 psia (96 Hrs)	77/0			
**T/C -65C/150C		-65C/+150C	(500 Cyc)	77/0			
Manufacturability		(Assembly S	ite)	Pass			
Moisture Sensitivity, L2		85C/60%RH	/168 Hrs	12/0			
Notes: ** Preconditioning sequence Level 2-260C							
Qual Device 2: ADS7871IDB (MSL 2-260C)							
Package Construction Details							
Assembly Site:	CAR		Mold Compound:	438358			
# Pins-Designator, Family:	28-DB, S	SOP	Mount Compound:	434165			
Leadframe (Finish, Base):	NiPdAu, (Cu	Bond Wire:	1.3 Mil Dia., AU			
Qualification:	ı 🛛 Te	est Results					
Reliability Test		Conditions		Sample Size/Fail			
**Unbiased HAST		130C/85%R	H/33.3 psia (96 Hrs)	77/0			
**T/C -65C/150C		-65C/+150C	(500 Cyc)	77/0			
Manufacturability		(Assembly S	ite)	Pass			
Moisture Sensitivity, L2		85C/60%RH	/168 Hrs	12/0			
Notes: ** Preconditioning sequence Level 2-260C							
Qual Device 3: ADS825E (MSL 2-260C)							
	Pa	ckage Const	truction Details				
Assembly Site:	CAR		Mold Compound:	438360			
# Pins-Designator, Family:	28-DB, S	SOP	Mount Compound:	434165			
Leadframe (Finish, Base):	NiPdAu, (Cu	Bond Wire:	1.3 Mil Dia., AU			
Qualification:	n 🛛 Te	est Results					
Reliability Test		Conditions		Sample Size/Fail			
Solderability		Pb-Free/Solo	der	22/0			
**Unbiased HAST		130C/85%R	H/33.3 psia (96 Hrs)	77/0			
**T/C -65C/150C		-65C/+150C	(500 Cyc)	77/0			
Manufacturability		(Assembly S		Pass			
Physical Dimensions		Mechanical o	drawing	5/0			
Moisture Sensitivity, L2		85C/60%RH		12/0			
Notes: ** Preconditioning	sequenc	e Level 2-260	OC				

Qual Device 4: DAC8820IBDB (MSL 2-260C)							
Package Construction Details							
Assembly Site:	CAR		Mold Compound:	438518			
# Pins-Designator, Family:	28-DB, 9	SSOP	434165				
Leadframe (Finish, Base):	NiPdAu,	Cu	1.3 Mil Dia., AU				
Qualification: Plan Test Results							
Deliahilita Teet		Conditions	Sample Size/Fail				
Reliability Test		Conditions	Lot 1	Lot 2	Lot 3		
Manufacturability		(Assembly S	Pass	Pass	Pass		
Solderability		8 Hrs/Stm A	22/0	22/0	-		
**Unbiased HAST		130C/85%R	77/0	77/0	77/0		
**T/C -65C/150C		-65C/+150C	77/0	77/0	77/0		
Physical Dimensions		Mechanical o	5/0	-	-		
Moisture Sensitivity, L2		85C/60%RH	12/0	12/0	-		
Notes: ** Preconditioning sequence Level 2-260C							
Qual Device 5: PGA2505IDB (MSL 2-260C)							
Package Construction Details							
Assembly Site:	CAR		438360				
# Pins-Designator, Family:	24-DB, 9	SSOP	434165				
Leadframe (Finish, Base):	NiPdAu,	Cu	1.3 Mil Dia., AU				
Qualification: Plan Test Results							
Reliability Test		Conditions	Sample Size/Fail				
**Unbiased HAST		130C/85%R	77/0				
**T/C -65C/150C		-65C/+150C	77/0				
Manufacturability		(Assembly S	Pass				
Physical Dimensions		Mechanical o	5/0				
Moisture Sensitivity, L2		85C/60%RH	12/0				
Notes: ** Preconditioning	sequenc	e Level 2-260	OC .				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com